

SiO₂ clad active and passive photonic crystal nanocavity devices fabricated with photolithography

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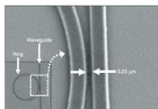
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Abstract

We describe the fabrication and a demonstration of passive and active photonic crystal nanocavity devices, namely an electro-optic modulator, an all-silicon photodetector and a DeMUX filter. This is the first demonstration of active and passive photonic crystal nanocavity devices fabricated with a photolithographic process that may lead to future mass production.

Background



Low energy : 25 pJ
Response time : ~450 ps

V.R. Almeida, et al., Nature 431, 1081 (2004)

Conversion E → O

- pn dope region
- Speed: 12.5 Gbit/s

Q. Xu, et al., Opt Exp. 15, 430 (2007)

Problems

1. EB-lithography
2. Air-bridge structure

Solution

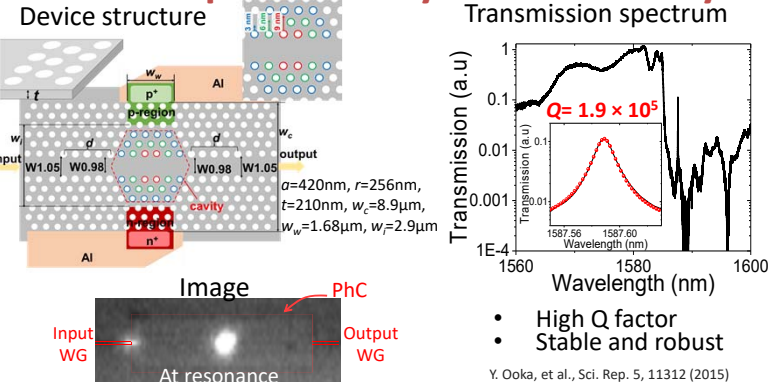
1. Photolithography fabrication w/ silica clad

PhC nanocavity
✓ High Q factor Q/V
✓ Small mode volume, V

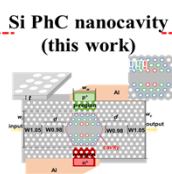
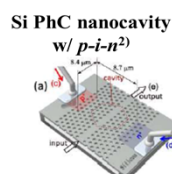
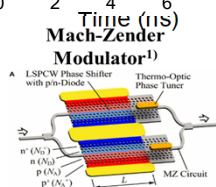
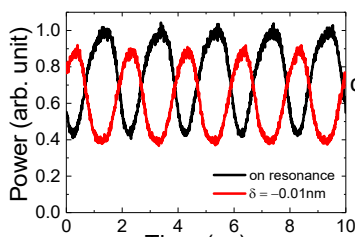
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Energy-efficient optical signal processing

Silica-clad photonic crystal nanocavity

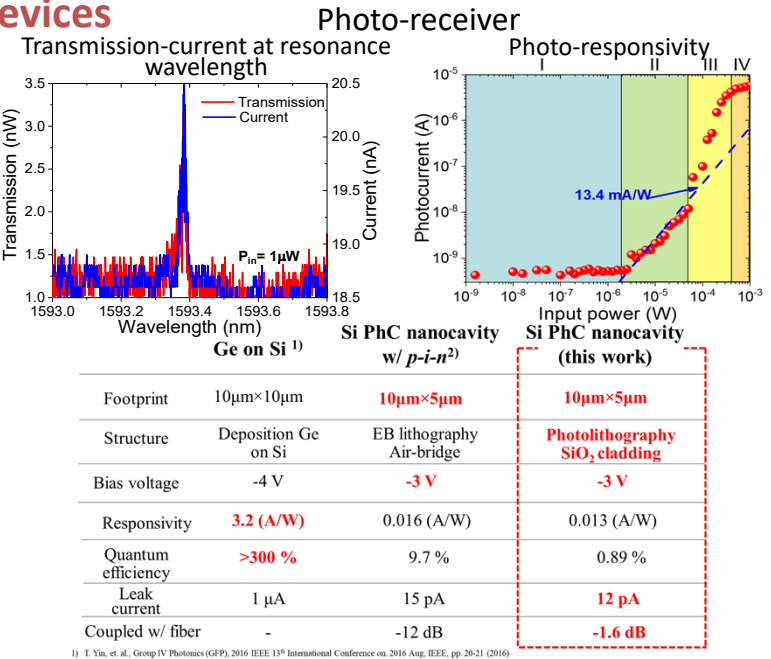


Electro-optic modulator

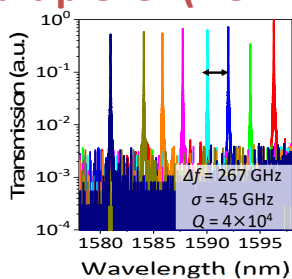
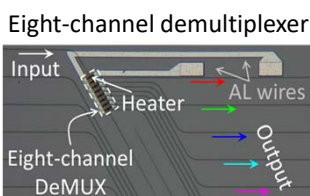


Fabrication process	Photolithography (easy)	EB lithography (complicated)	Photolithography (easy)
Structure	Silica clad	Air-bridge	Silica clad
Size	400 μm × 500 μm	10 μm × 5 μm	10 μm × 5 μm
Speed	10GHz	100GHz	100GHz
Voltage	5V	2V	2V

Active devices



Passive device : Demultiplexer (DeMUX)



Stability & Structure	Fabrication	# of channels	Channel spacing	Configuration	Footprint per channel	Other remarks	Reference
High & PhC SiO ₂ clad	Photo-lithography	8	267 GHz	In-plane	110 μm^2	WM cavity	This work
Low & PhC Air-bridge	EB lithography	5	3.7 THz	In-plane	30 μm^2	L3 cavity	OE 14, 12394 (2006)
Low & PhC Air-bridge	EB lithography	32	100 GHz	Out-plane	100 μm^2	L3 cavity	OE 22, 4698 (2014)
High & Si-AWG	Photo-lithography	8	250 GHz	In-plane	1700 μm^2	-	OE 22, 4698 (2014)

Summary

1. We demonstrated the active and passive devices fabricated using photolithographic SiO₂ clad PhC nanocavity devices.
2. We showed that 0.5 GHz modulation is possible with a p-i-n integrated PhC nanocavity.
3. We also obtained 13.4 mA/W responsivity for the photodetector at input powers of less than 10 μW and low dark current.
4. Finally, we demonstrated of a multichannel passive DeMUX filter with SiO₂ clad photolithographic PhC nanocavity.

Acknowledgement & Publications

This work was supported by the Strategic Information and Communications R&D Promotion Programme (SCOPE) #152103015, from Ministry of Internal Affairs and Communication, Japan. The author has been partially supported by Keio Leading-edge Laboratory (KLL) of Science and Technology Center

1. N.A.B. Daud, et al., "Electro-Optic Modulator Based on Photolithography Fabricated p-i-n Integrated Photonic Crystal", IEICE Transaction on Electronics, (2017) (accepted)
2. Y. Ooka, N. A. B. Daud, et al., "Ultrasmall in-plane photonic crystal demultiplexers fabricated with photolithography", Opt. Express 25, 1521-8 (2017).